

# MOS Capacitors

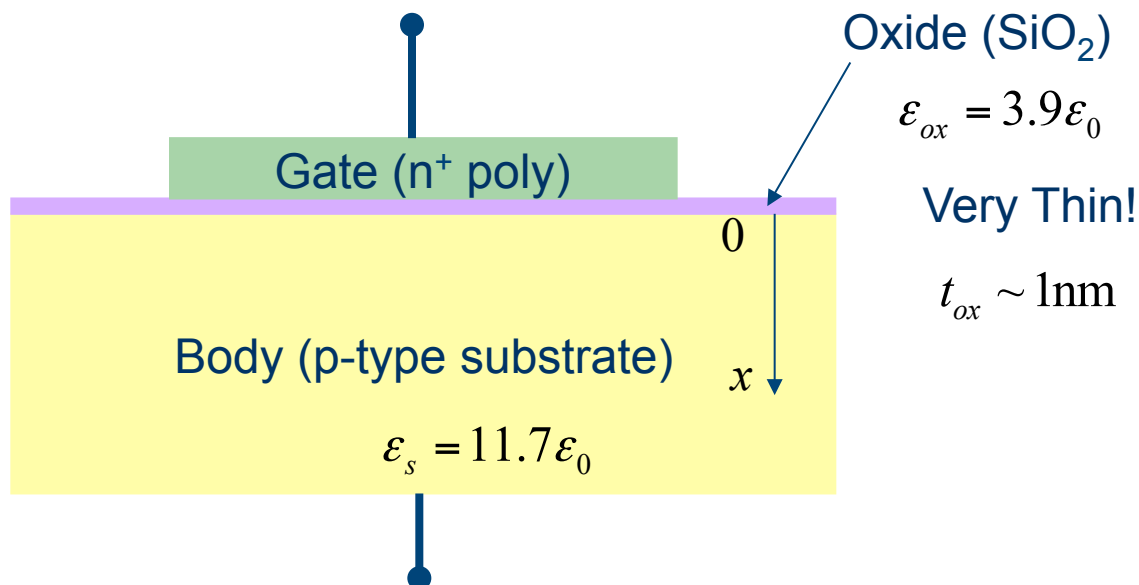
**Prof. Ali M. Niknejad**  
**Prof. Rikky Muller**

# Announcements

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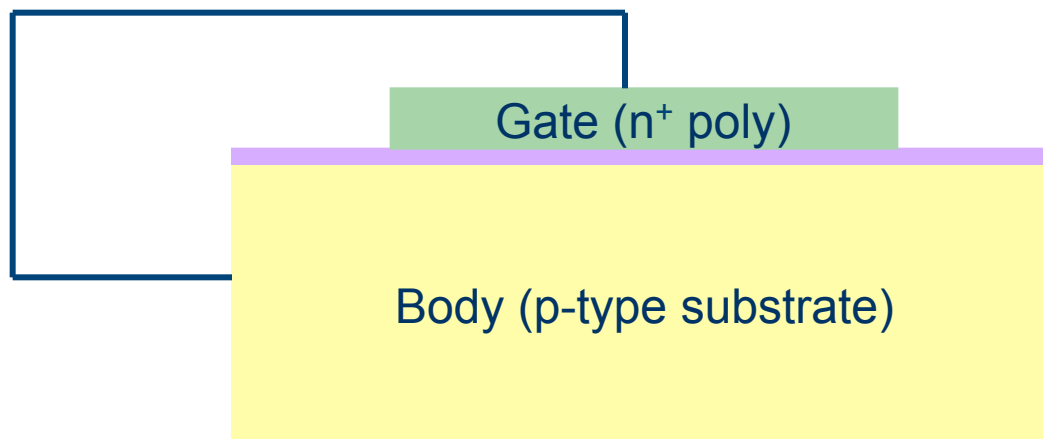
- Welcome to the second half of EE105!
- Professor Muller will be lecturing
- Midterm 1 handed back today
- Mean =
- Median =
- Standard Dev =
- Midterm 2 on Thursday, March 23 in lecture
- Attend discussion sessions! They are helpful for homework, exam reviews and topics not covered in lecture.

# MOS Capacitor



- MOS = Metal Oxide Semiconductor
- Sandwich of conductors separated by an insulator
- “Metal” is more commonly a heavily doped polysilicon (poly-Si) layer  $n^+$  or  $p^+$  layer
  - *Was metal (e.g. Al) until ~1970 but changed to poly-Si due to high temperature processing. After 2008, metal gates have been reintroduced!*  
*Learn more about MOS process technology in EE130 & EE143*
- NMOS  $\rightarrow$  p-type substrate, PMOS  $\rightarrow$  n-type substrate

# Metal-Oxide-Semi Junction

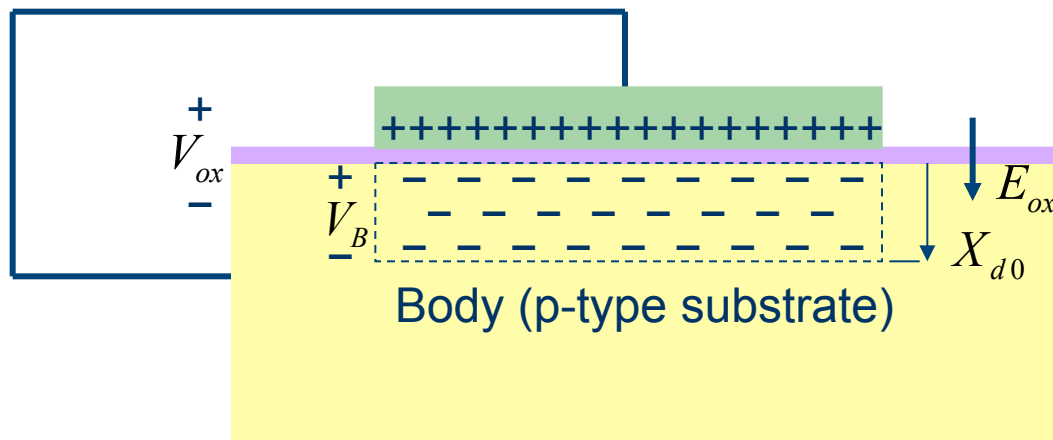


- Under thermal equilibrium, the n-type poly gate is at a higher potential than the p-type substrate

$$\phi_p = -\frac{kT}{q} \ln \frac{N_a}{n_i} \quad \phi_{poly, n^+} = \frac{kT}{q} \ln \left( \frac{N_{d, poly}}{n_i} \right) \approx 550 \text{mV}$$

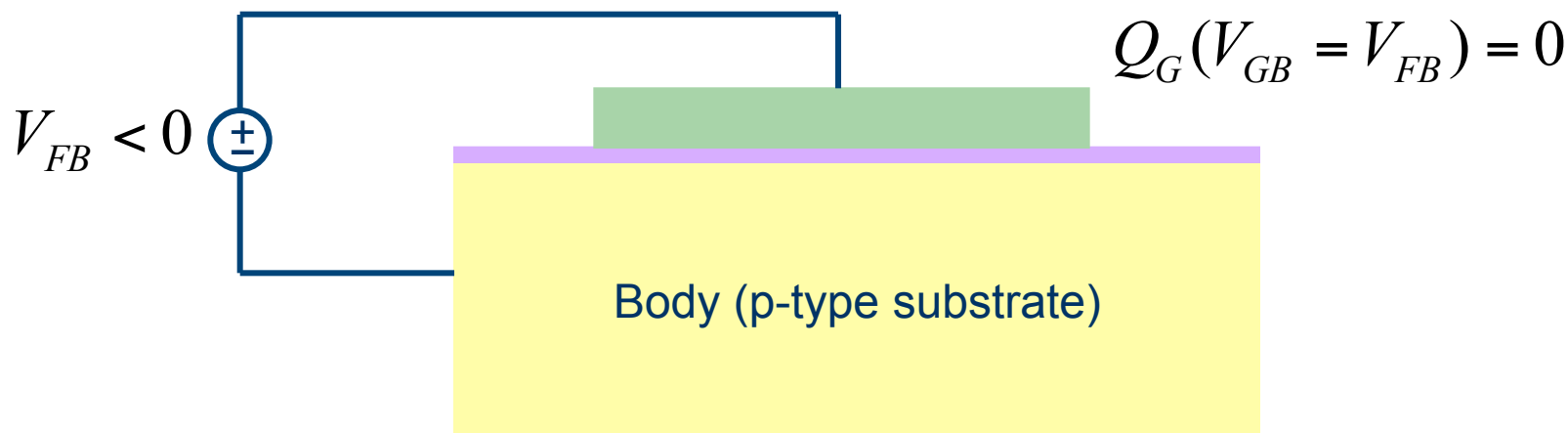
- No current can flow because of the insulator but this potential difference is accompanied with an electric field
- Fields terminate on charge!

# Fields and Charge at Equilibrium



- At equilibrium there is an electric field from the gate to the body
- Need a positive charge on the gate, negative charge in substrate
- Since body is p-type, negative charges in the body come from a depletion region

# Flat Band Voltage, $V_{GB} = V_{FB}$

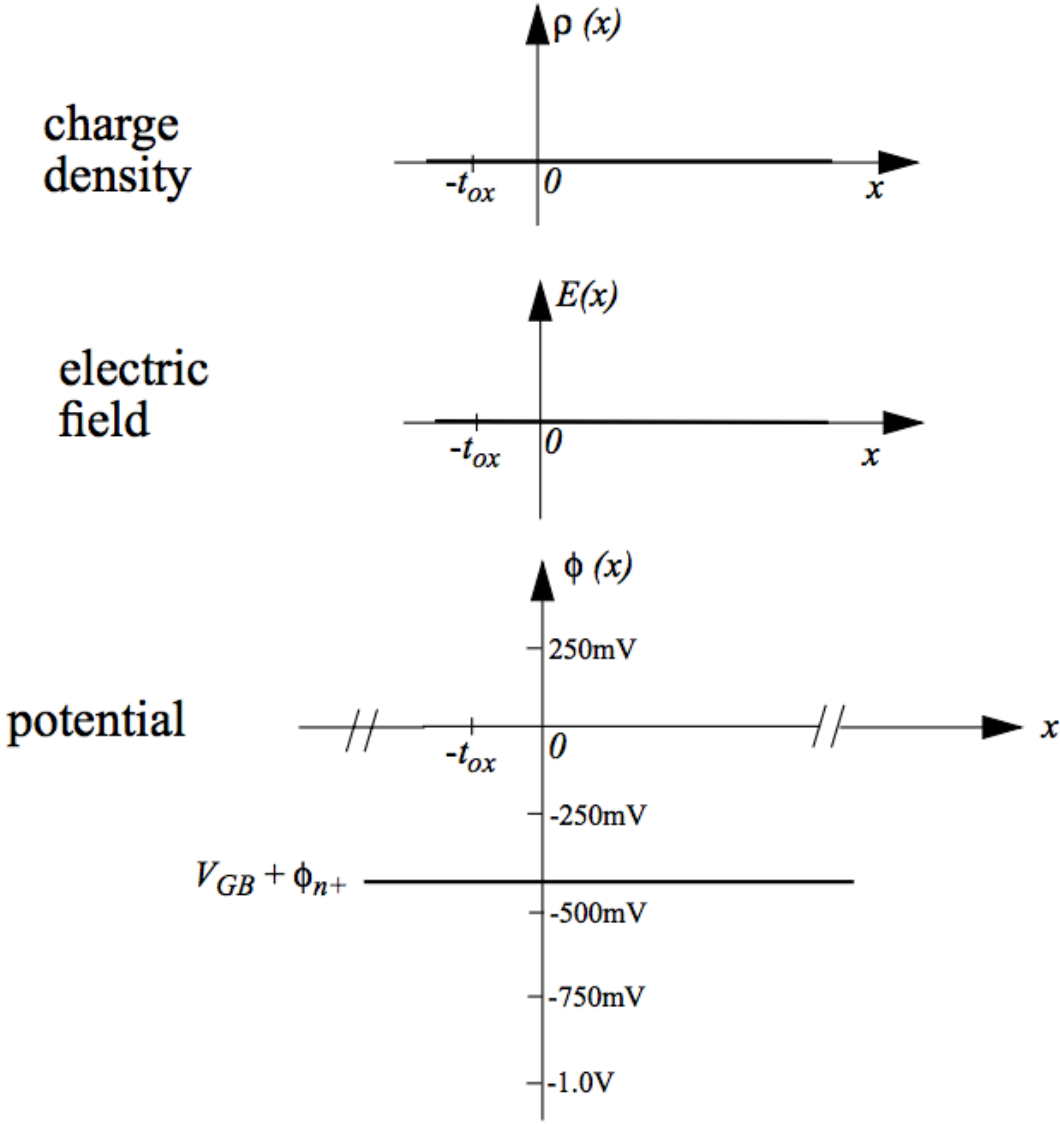


- If we apply a bias, we can compensate for this built-in potential

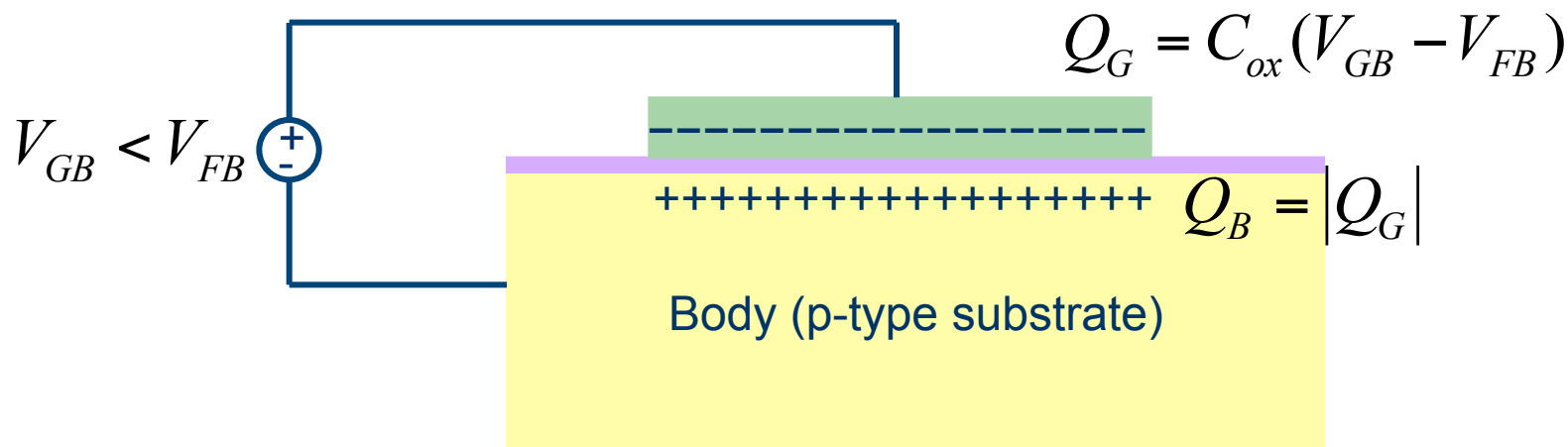
$$V_{FB} = -(\phi_{n^+} - \phi_p)$$

- In this case the charge on the gate goes to zero and the depletion region disappears
- In solid-state physics lingo, the energy bands are “flat” under this condition

# Flat Band Voltage, $V_{GB} = V_{FB}$



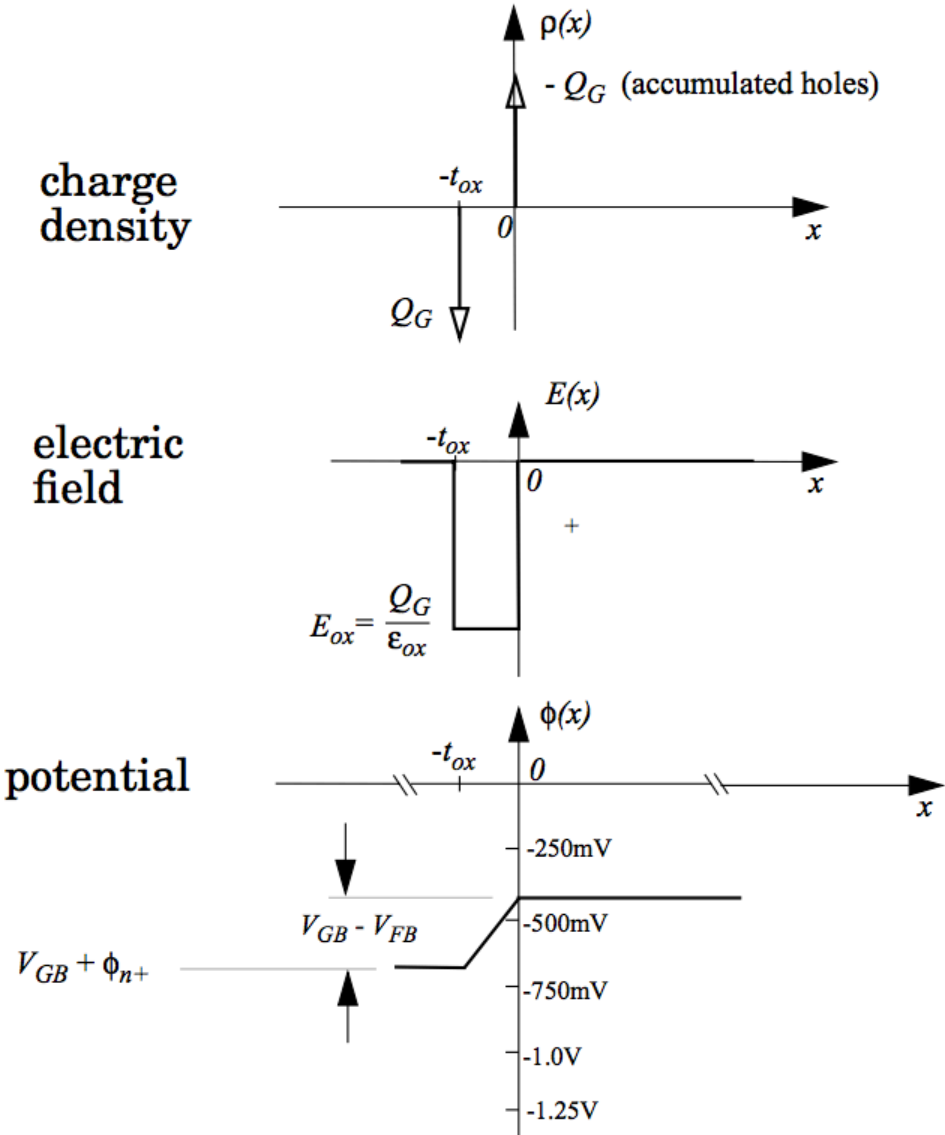
# Accumulation, $V_{GB} < V_{FB}$



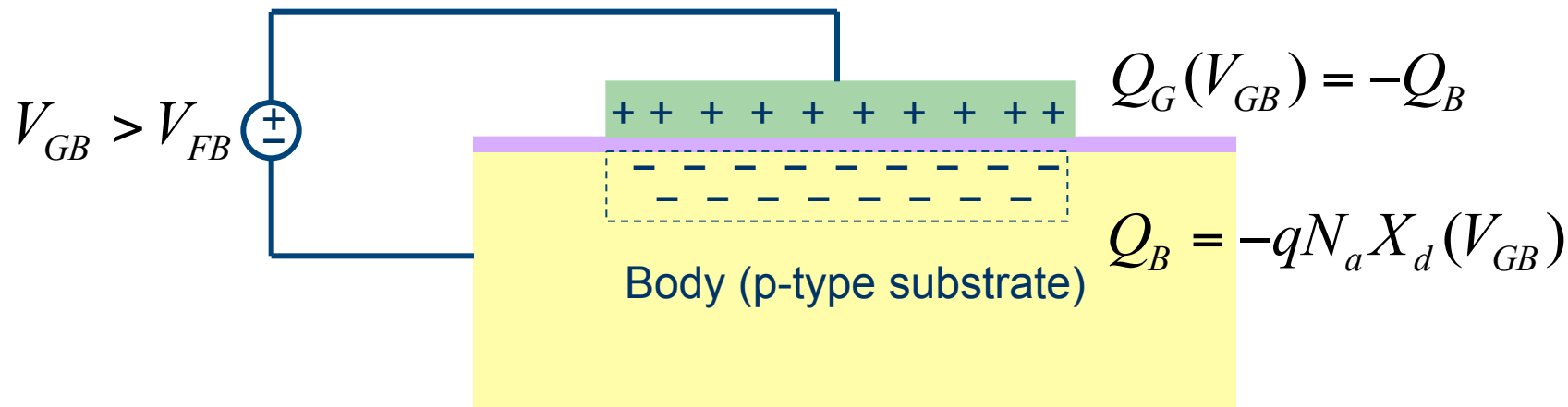
- If we further decrease the potential beyond the “flat-band” condition, we essentially have a parallel plate capacitor
- Plenty of holes and electrons are available to charge up the plates
- Negative bias attracts holes under gate



# Accumulation, $V_{GB} < V_{FB}$

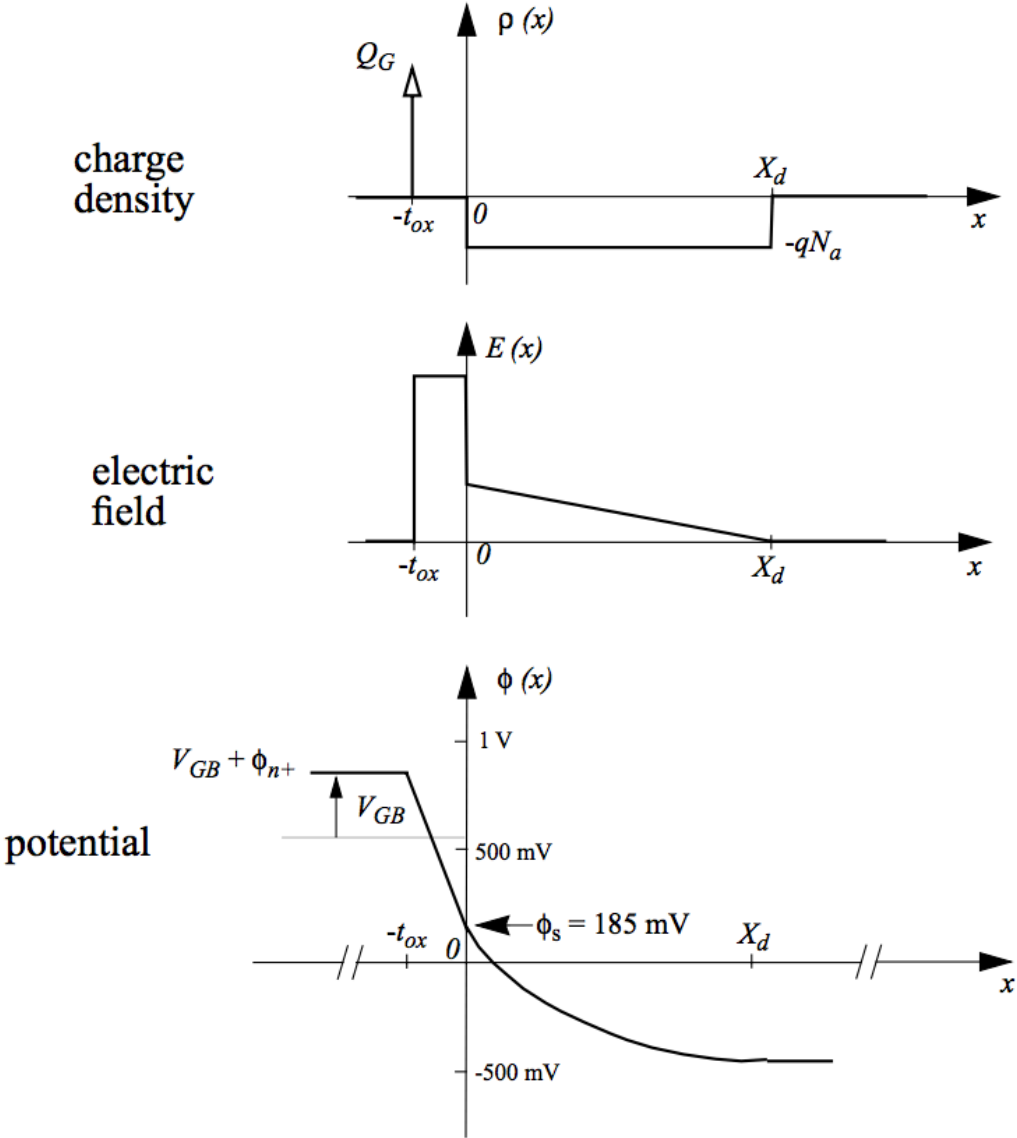


# Depletion, $V_{GB} > V_{FB}$

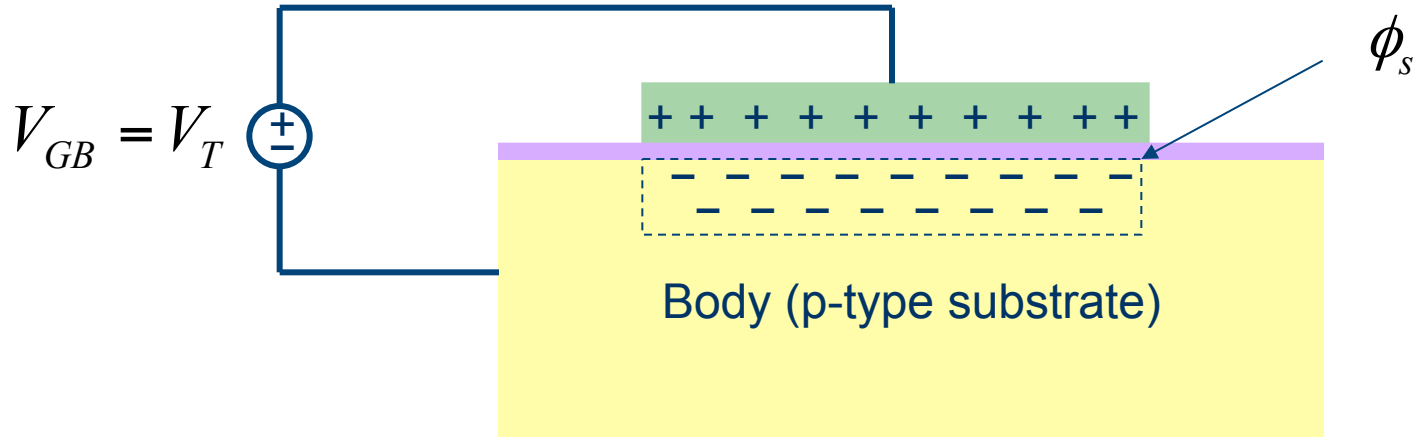


- Similar to equilibrium, the potential in the gate is higher than the body
- Body charge is made up of the depletion region ions
- Potential drop across the body and depletion region

# Depletion, $V_{GB} > V_{FB}$



# Inversion, $V_{GB} > V_T$



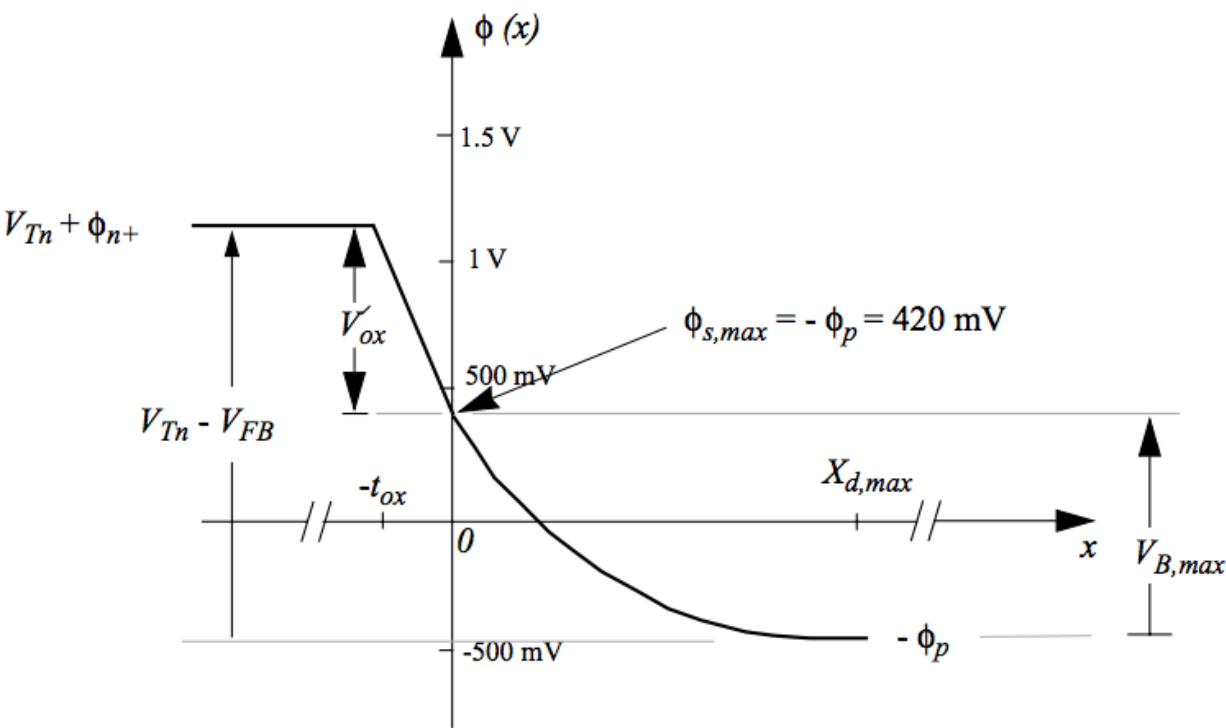
- As we further increase the gate voltage, eventually the surface potential increases to a point where the electron density at the surface equals the background ion density

$$n_s = n_i e^{\frac{q\phi_s}{kT}} = N_a \quad \longrightarrow \quad \phi_s = -\phi_p$$

- At this point, the depletion region stops growing and the extra charge is provided by the inversion charge at surface
- “Inversion” meaning that the surface is effectively n-type

# Inversion, $V_{GB} > V_T$

$$\phi_{s,max} = -\phi_p$$



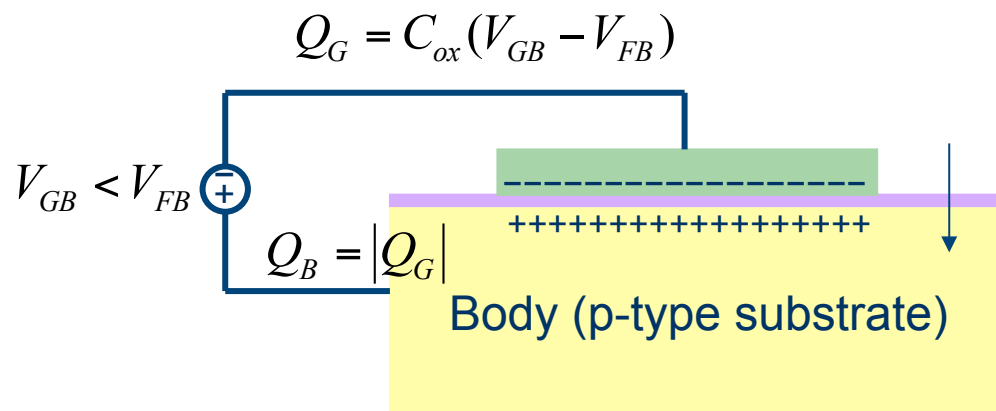
# Threshold Voltage

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- The threshold voltage is defined as the gate-body voltage that causes the surface to change from p-type to n-type
- For this condition, the surface potential has to equal the negative of the p-type potential
- We can derive that this voltage is equal to:

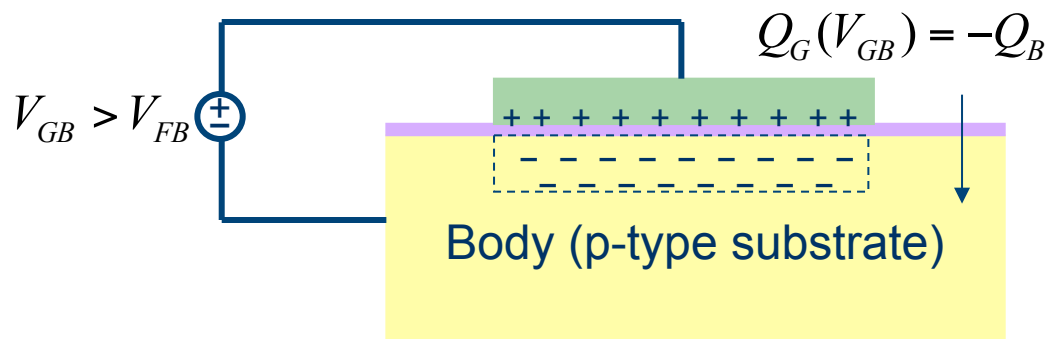
$$V_{Tn} = V_{FB} - 2\phi_p + \frac{1}{C_{ox}} \sqrt{2q\epsilon_s N_a (-2\phi_p)}$$

# Recap Accumulation: $V_{GB} < V_{FB}$



- Essentially a parallel plate capacitor
- Capacitance is determined by oxide thickness

# Recap Depletion: $V_{FB} < V_{GB} < V_T$

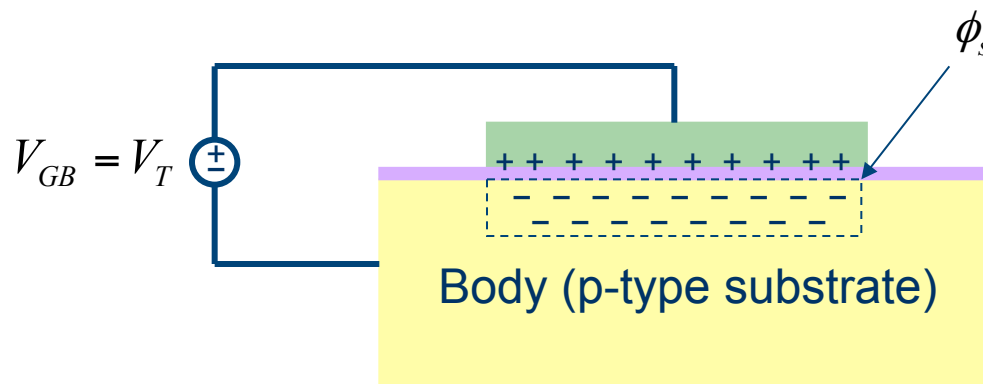


$$Q_B = -qN_a X_d(V_{GB})$$

- Positive charge on gate terminates on negative charges in depletion region
- Potential drop across the oxide and depletion region
- Charge has a square-root dependence on applied bias



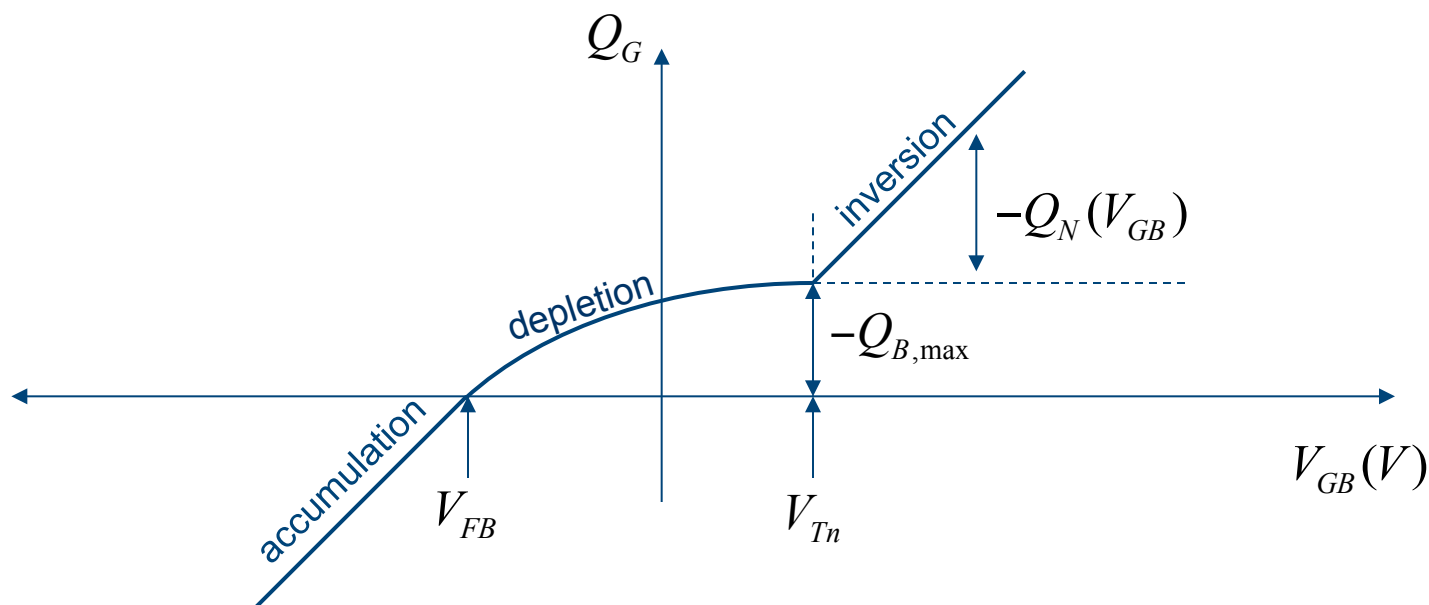
# Recap Inversion: $V_{GB} > V_T$



$$n_s = n_i e^{\frac{q\phi_s}{kT}} = N_a$$

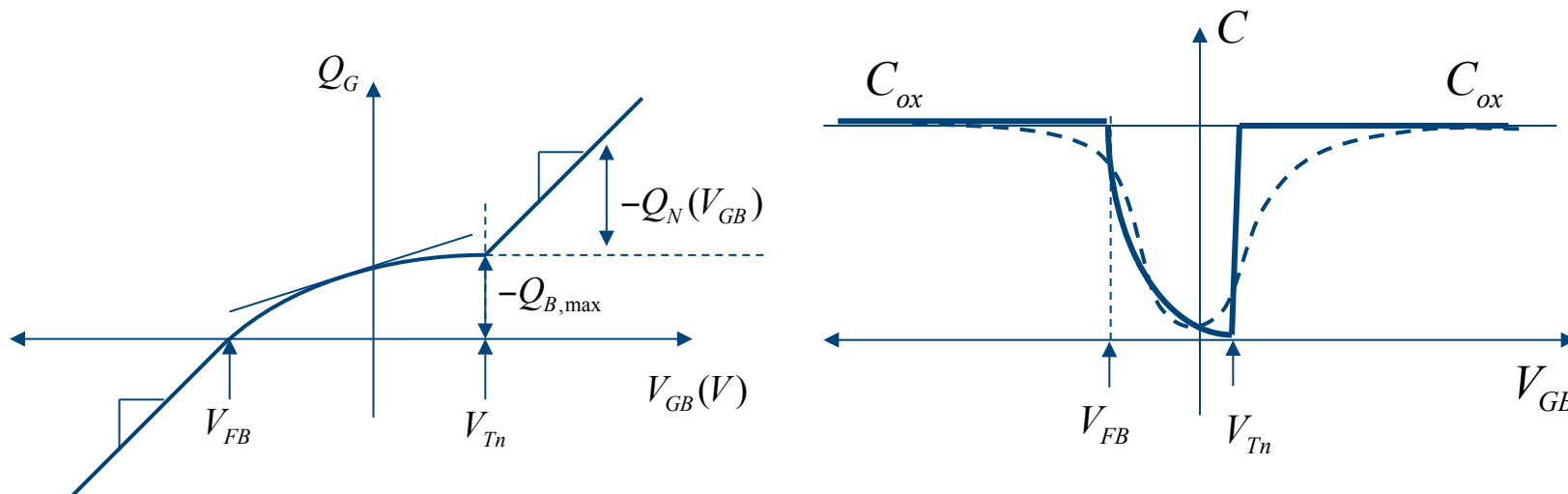
- The surface potential increases to a point where the electron density at the surface equals the background ion density
- At this point, the depletion region stops growing and the extra charge is provided by the inversion charge (electrons) at the surface

# Q-V Curve for MOS Capacitor



- In accumulation, the charge is simply proportional to the applied gate-body bias
- In inversion, the same is true
- In depletion, the charge grows slower since the voltage is applied over a depletion region

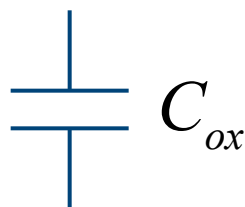
# MOS CV Curve



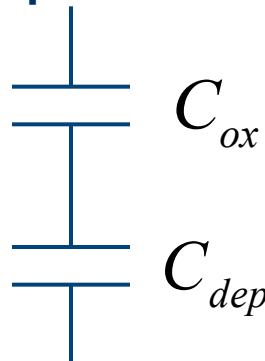
- Small-signal capacitance is slope of Q-V curve
- Capacitance is constant in accumulation and inversion
- Capacitance in the depletion region is smallest
- Capacitance is non-linear in depletion

# C-V Curve Equivalent Circuits

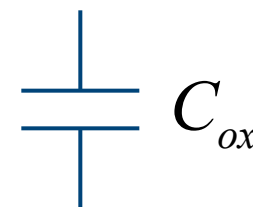
Accumulation



Depletion



Inversion



$$C_{dep} = \frac{\epsilon_s}{x_{dep}}$$

$$C_{tot} = \frac{C_{dep} C_{ox}}{C_{dep} + C_{ox}} = \frac{C_{ox}}{1 + \frac{C_{dep}}{C_{ox}}} = \frac{C_{ox}}{1 + \frac{\epsilon_s t_{ox}}{\epsilon_{ox} x_{dep}}}$$

- In accumulation mode the capacitance is just due to the voltage drop across  $t_{ox}$
- In depletion region, the voltage drop is across the oxide and the depletion region
- In inversion the incremental charge comes from the inversion layer (depletion region stops growing).

# Numerical Example

- MOS Capacitor with p-type substrate:

$$t_{ox} = 20\text{nm} \quad N_a = 5 \times 10^{16} \text{cm}^{-3}$$

- Calculate flat-band:

$$V_{FB} = -(\phi_{n^+} - \phi_p) = -(550 - (-402)) = -0.95\text{V}$$

- Calculate threshold voltage:

$$C_{ox} = \frac{\epsilon_{ox}}{t_{ox}} = \frac{3.45 \times 10^{-13} \text{F/cm}}{2 \times 10^{-6} \text{cm}}$$

$$V_{Tn} = V_{FB} - 2\phi_p + \frac{1}{C_{ox}} \sqrt{2q\epsilon_s N_a (-2\phi_p)}$$

$$V_{Tn} = -.95 - 2(-0.4) + \frac{\sqrt{2 \times 1.6 \times 10^{-19} \times 1.04 \times 10^{-12} \times 5 \times 10^{16} \times 2 \times 0.4}}{C_{ox}} = 0.52\text{V}$$

# Num Example: Electric Field in Oxide

- Apply a gate-to-body voltage:

$$V_{GB} = -2.5 < V_{FB}$$

- Device is in accumulation
- The entire voltage drop is across the oxide:

$$E_{ox} = \frac{V_{ox}}{t_{ox}} = \frac{V_{GB} + \phi_{n^+} - \phi_p}{t_{ox}} = \frac{-2.5 + 0.55 - (-0.4)}{2 \times 10^{-6}} = -8 \times 10^5 \frac{\text{V}}{\text{cm}}$$

- The charge in the substrate (body) consist of holes:

$$Q_B = -C_{ox}(V_{GB} - V_{FB}) = 2.67 \times 10^{-7} \text{ C/cm}^2$$